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Buthan W. Werse

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## IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re applica	tion of:	
Applicant:	K. Sahota, D. Schonauer, J. Groschopf, G. Marxsen, and S. Avanzino,	) ) Grp Art Unit: 1765
	G. Marxsen, and S. Avanzino,	) Oip Ait Oilt. 1703
Assignee:	Advanced Micro Devices, Inc.	) Exam: L. Umez Eronini
Serial Numb	er: 09/749,191	)
Filed:	December 26, 2000	) )
For:	PREVENTION OF PRECIPITATION DEFECTS ON COPPER INTER- CONNECTS DURING CMP BY USE OF SOLUTIONS CONTAINING ORGANIC COMPOUNDS WITH SILICA ADSORPTION AND COPPER CORROSION INIHIBITING PROPERTIES	C 1 (00 FIAIL ROOM  O 1 (00 FIAIL ROOM  O 1 (00 O O O O O O O O O O O O O O O O O O

Assistant Commissioner for Patents Washington, D.C. 20231

## **RESPONSE TO OFFICE ACTION**

Dear Sir,

This is in response to the Office Action mailed on December 19, 2002.